Form PTO 1449		U.S. DEPARTME	U.S. DEPARTMENT OF COMMERCE	ATTY DOCKET NO. SERIAL NO.				
Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE			241235US3X	f .				
			241235US3X New Application					
LIST OF REFERENCES CITED BY APPLICANT				Chuichi ISHIBASHI, et al.				
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015	AB	6,101,853	08/15/2000	D. L. HERR					
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